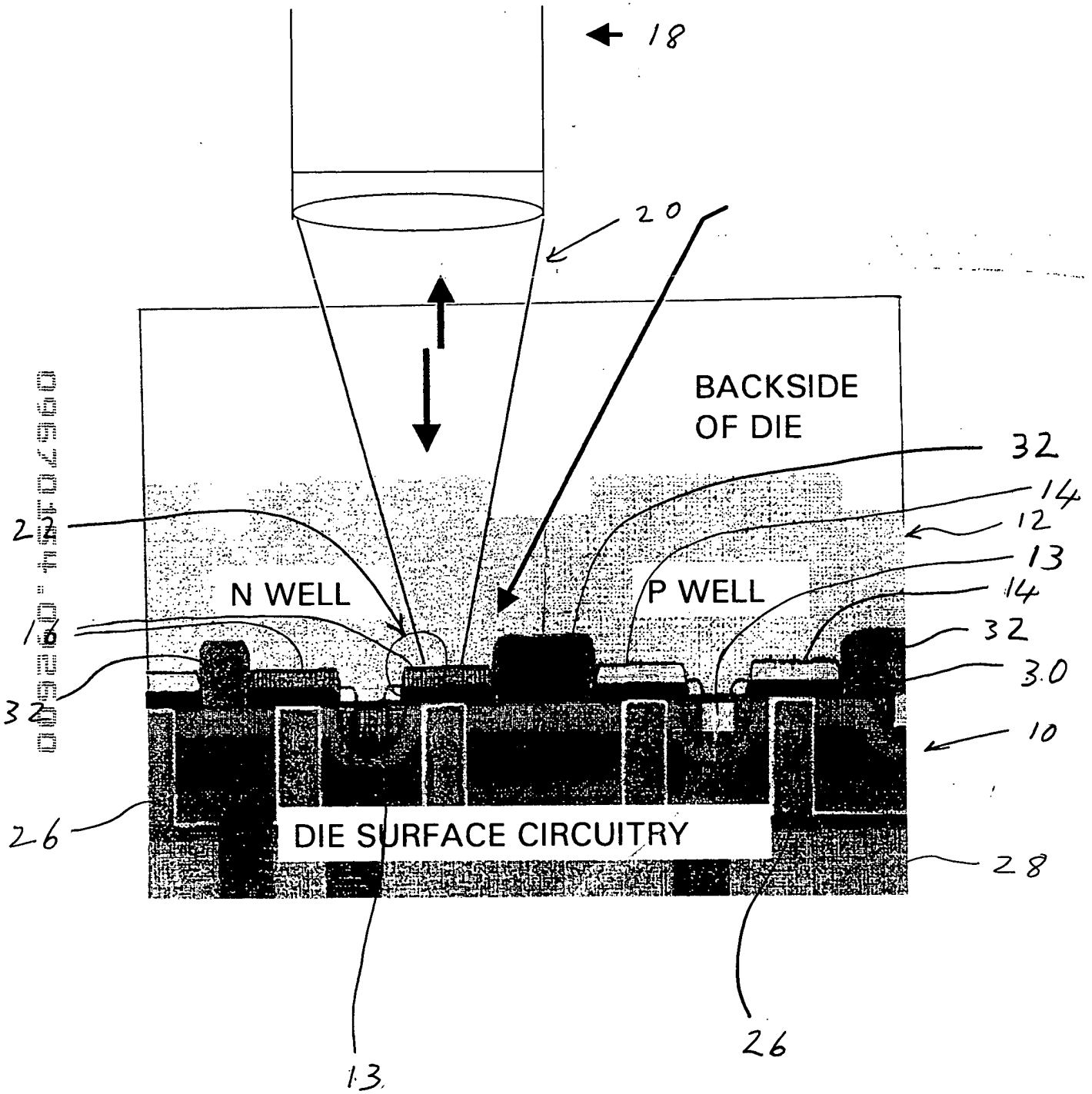

18
20
BACKSIDE
OF DIE
32
14
12
13
14
32
30
10
22
N WELL
P WELL
16
32
26
DIE SURFACE CIRCUITRY
28
13
26

Fig 1

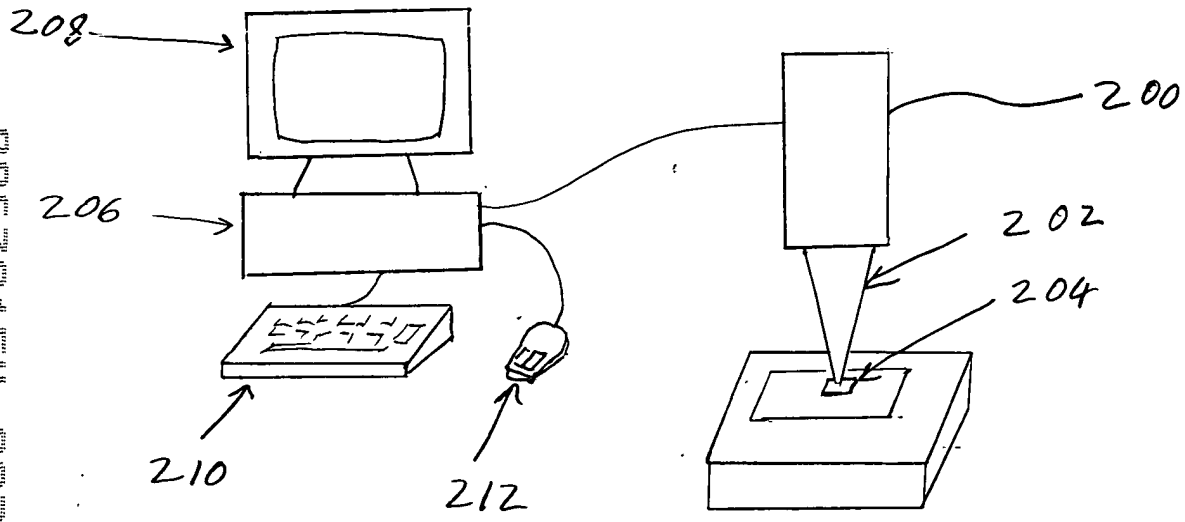
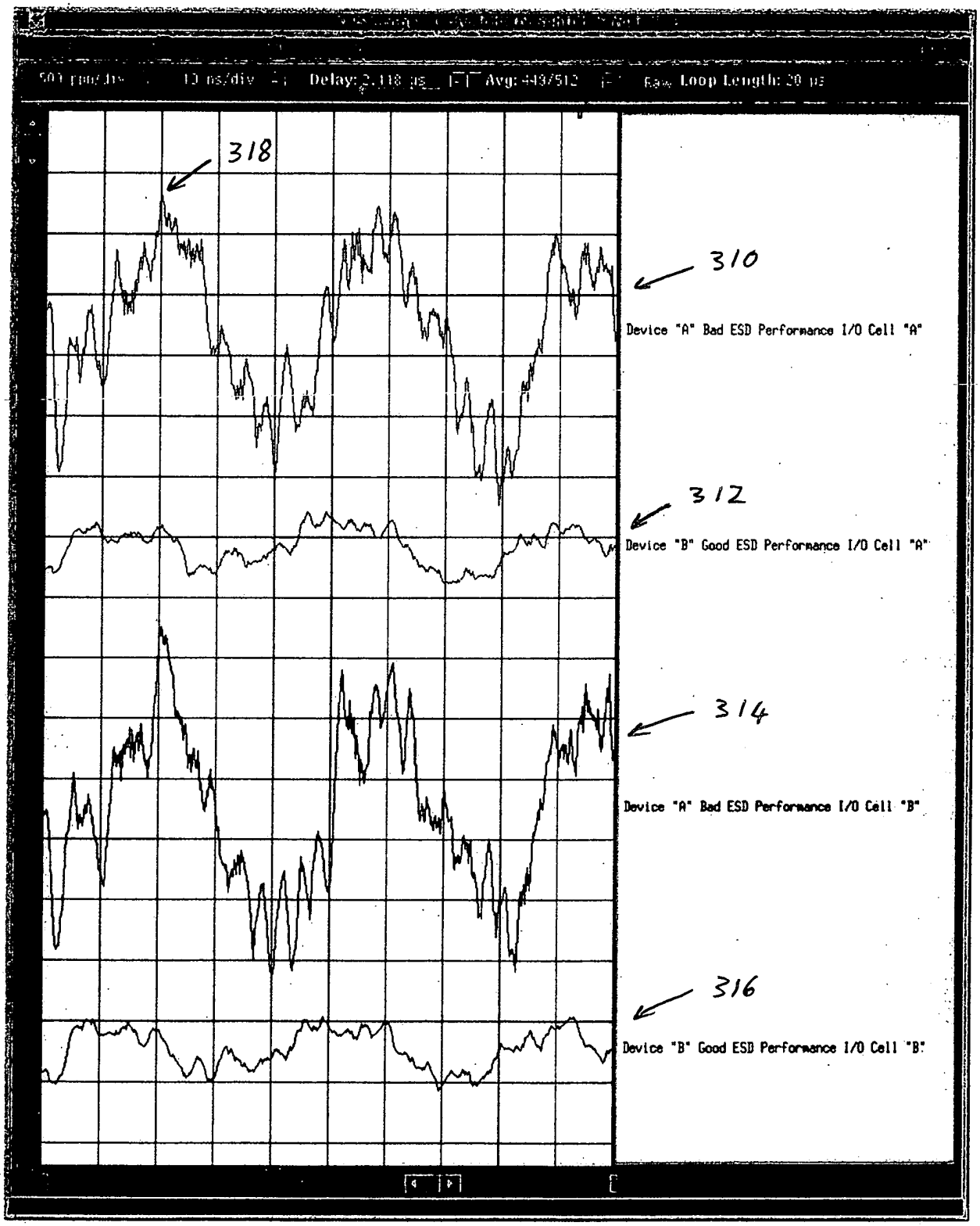


Fig 2


Delay:
Avg:
Loop Length:
318
310
Device "A" Bad ESD Performance I/O Cell "A"
312
Device "B" Good ESD Performance I/O Cell "A"
314
Device "A" Bad ESD Performance I/O Cell "B"
316
Device "B" Good ESD Performance I/O Cell "B"

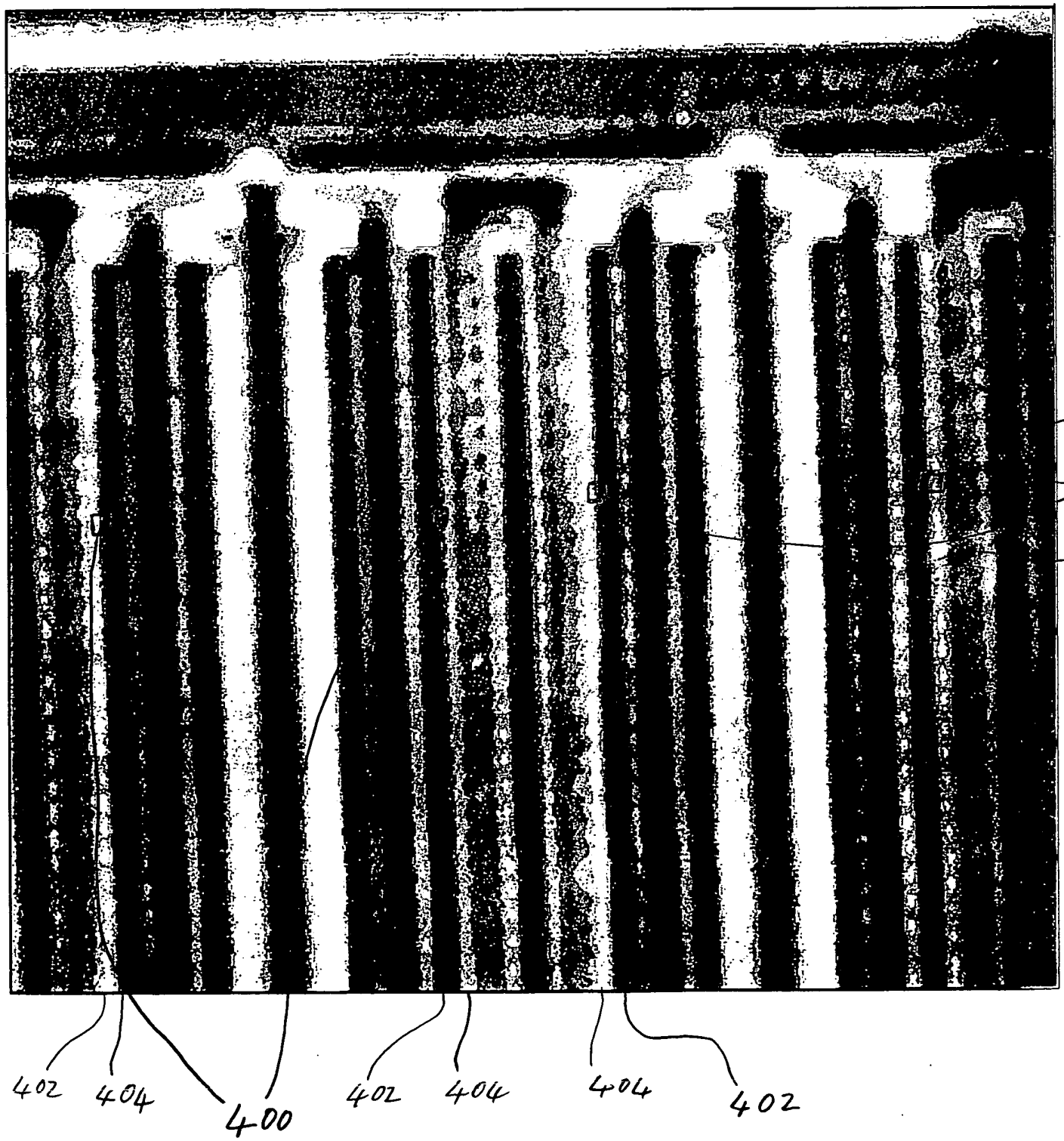



Fig 4